

Appendix 1

List of Newly Established and Revised JIS Publicly Notified on August 20, 2025

< Division in charge and telephone number >

International Standardization Division (e-mail: bzl-s-kijun-ISO@meti.go.jp Tel:03-3501-1511 ext.3423～3427)

International Electrotechnology Standardization Division (e-mail: bzl-s-iec@meti.go.jp Tel: 03- 3501-1511 ext. 3428～3429)

1. Newly established standards

(Japanese Industrial Standards Committee)

| Name of standard | JIS code | Association that prepared the draft proposal | Division in charge |
|---|----------|--|--|
| Machine tools-Environmental evaluation of machine tools-Part 4: Principles for measuring metal-forming machine tools and laser processing machine tools with respect to energy efficiency | B0955-4 | Japan Forming Machinery Association | International Standardization Division |

(Submitted by Accredited SDO-Japanese Standards Association)

| Name of standard | JIS code | Association that prepared the draft proposal | Division in charge |
|--|-------------|--|--|
| Fire hazard testing-Part 1-12: Guidance for assessing the fire hazard of electrotechnical products-Fire safety engineering | C60695-1-12 | Japanese Standards Association | International Electrotechnology Standardization Division |
| Fire hazard testing-Part 1-20: Guidance for assessing the fire hazard of electrotechnical products-Ignitability-General guidance | C60695-1-20 | Japanese Standards Association | International Electrotechnology Standardization Division |
| Fiber optic sensors-Part 2-2: Temperature measurement-Distributed sensing | C61757-2-2 | Japanese Standards Association | International Electrotechnology Standardization Division |
| Methods for product accelerated testing | C62506 | Japanese Standards Association | International Electrotechnology Standardization Division |
| Information technology-Artificial intelligence-Management system | Q42001 | Japanese Standards Association | International Electrotechnology Standardization Division |
| Information technology-Vocabulary-Biometrics | X0037 | Japanese Standards Association | International Electrotechnology Standardization Division |
| Trustworthiness-Vocabulary | X0061 | Japanese Standards Association | International Electrotechnology Standardization Division |
| Information technology-Generic cabling for customer premises-Part 4: Single-tenant homes | X5150-4 | Japanese Standards Association | International Electrotechnology Standardization Division |

| Name of standard | JIS code | Association that prepared the draft proposal | Division in charge |
|---|----------|--|--|
| Information technology-Generic cabling for customer premises-Part 5: Data centres | X5150-5 | Japanese Standards Association | International Electrotechnology Standardization Division |
| Internet of Things (IoT) and digital twin-Vocabulary | X20924 | Japanese Standards Association | International Electrotechnology Standardization Division |

(Total standards newly established: 11)

2. Revised standards

(Japanese Industrial Standards Committee)

| Name of standard | JIS code | Association that prepared the draft proposal | Division in charge |
|---|------------|---|--|
| Test code for machine tools-Part 10: Determination of the measuring performance of probing systems of numerically controlled machine tools | B6190-10 | Japan Machine Tool Builders' Association | International Standardization Division |
| Testing methods for performance of pump using model pump | B8327 | The Japan Society Of Industrial Machinery Manufacturers | International Standardization Division |
| Safety of laser products-Equipment classification and requirements | C6802 | Optoelectronics Industry And Technology Development Association | International Electrotechnology Standardization Division |
| Glossary of terms for photovoltaic power generation | C8960 | The Japan Electrical Manufacturers' Association | International Electrotechnology Standardization Division |
| Terrestrial photovoltaic (PV) modules-Design qualification and type approval-Part 1: Test requirements | C61215-1 | The Japan Electrical Manufacturers' Association | International Electrotechnology Standardization Division |
| Terrestrial photovoltaic (PV) modules-Design qualification and type approval-Part 1-1: Special requirements for testing of crystalline silicon photovoltaic (PV) modules | C61215-1-1 | The Japan Electrical Manufacturers' Association | International Electrotechnology Standardization Division |
| Terrestrial photovoltaic (PV) modules-Design qualification and type approval-Part 1-2: Special requirements for testing of thin-film Cadmium Telluride (CdTe) based photovoltaic (PV) modules | C61215-1-2 | The Japan Electrical Manufacturers' Association | International Electrotechnology Standardization Division |
| Terrestrial photovoltaic (PV) modules-Design qualification and type approval-Part 1-3: Special requirements for testing of thin-film amorphous silicon based photovoltaic (PV) modules | C61215-1-3 | The Japan Electrical Manufacturers' Association | International Electrotechnology Standardization Division |
| Terrestrial photovoltaic (PV) modules-Design qualification and type approval-Part 1-4: Special | C61215-1-4 | The Japan Electrical Manufacturers' Association | International Electrotechnology Standardization |

| Name of standard | JIS code | Association that prepared the draft proposal | Division in charge |
|--|----------|---|--|
| requirements for testing of thin-film Cu(In, Ga) (S, Se) ₂ based photovoltaic (PV) modules | | | Division |
| Terrestrial photovoltaic (PV) modules - Design qualification and type approval - Part 2: Test procedures | C61215-2 | The Japan Electrical Manufacturers' Association | International Electrotechnology Standardization Division |
| Facility management-Management systems-Requirements with guidance for use | Q41001 | Japan Facility Management Association | International Standardization Division |
| Optics and photonics-Optical materials and components-Test method for homogeneity of optical glasses by laser interferometry | R3252 | Japan Optical Glass Manufacturers' Association | International Standardization Division |

(Submitted by Accredited SDO-Japanese Standards Association)

| Name of standard | JIS code | Association that prepared the draft proposal | Division in charge |
|--|-------------|--|--|
| Fixed capacitors for use in electronic equipment-Part 11: Sectional specification-Fixed polyethylene-terephthalate film dielectric metal foil DC capacitors | C5101-11 | Japanese Standards Association | International Electrotechnology Standardization Division |
| Fixed resistors for use in electronic equipment-Part 8: Sectional specification: Fixed surface mount resistors | C5201-8 | Japanese Standards Association | International Electrotechnology Standardization Division |
| Potentiometers for use in electronic equipment-Part 3: Sectional specification: Rotary precision potentiometers | C5260-3 | Japanese Standards Association | International Electrotechnology Standardization Division |
| Connectors for electrical and electronic equipment-Tests and measurements-Part 1-100: General-Applicable publications | C5402-1-100 | Japanese Standards Association | International Electrotechnology Standardization Division |
| Connectors for electrical and electronic equipment-Tests and measurements-Part 23-3: Screening and filtering tests-Test 23c: Shielding effectiveness of connectors and accessories | C5402-23-3 | Japanese Standards Association | International Electrotechnology Standardization Division |
| Fiber optic chromatic dispersion compensator using single-mode dispersion compensating fiber | C5916-3 | Japanese Standards Association | International Electrotechnology Standardization Division |
| Optical amplifiers-Test methods-Part 3-2: Noise figure parameters-Electrical spectrum analyzer method | C6122-3-2 | Japanese Standards Association | International Electrotechnology Standardization Division |
| Optical amplifiers-Test methods-Part 4-1: Transient parameters-Measurement of gain parameters using two-wavelength method | C6122-4-1 | Japanese Standards Association | International Electrotechnology Standardization Division |

| Name of standard | JIS code | Association that prepared the draft proposal | Division in charge |
|---|-------------|--|--|
| Optical amplifiers-Test methods-Part 4-3: Power transient parameters-Single channel optical amplifiers in output power control | C6122-4-3 | Japanese Standards Association | International Electrotechnology Standardization Division |
| Environmental testing-Part 2-14: Tests-Test N: Change of temperature | C60068-2-14 | Japanese Standards Association | International Electrotechnology Standardization Division |
| Environmental testing-Part 2-17: Tests-Test Q: Sealing | C60068-2-17 | Japanese Standards Association | International Electrotechnology Standardization Division |
| Environmental testing-Part 3-4: Supporting documentation and guidance-Damp heat tests | C60068-3-4 | Japanese Standards Association | International Electrotechnology Standardization Division |
| Classification of environmental conditions-Part 3-4: Classification of groups of environmental parameters and their severities-Stationary use at non-weatherprotected locations | C60721-3-4 | Japanese Standards Association | International Electrotechnology Standardization Division |
| Information technology-Service management-Part 1: Service management system requirements | Q20000-1 | Japanese Standards Association | International Electrotechnology Standardization Division |
| Security and resilience-Business continuity management systems-Requirements | Q22301 | Japanese Standards Association | International Standardization Division |
| Systems and software engineering-System life cycle processes | X0170 | Japanese Standards Association | International Electrotechnology Standardization Division |
| Cards and security devices for personal identification-Test methods-Part 1: General characteristics | X6305-1 | Japanese Standards Association | International Electrotechnology Standardization Division |

(Total standards revised: 29)

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